

IEC QUALITY ASSESSMENT SYSTEM (IECQ)

covering Electronic Components,
Assemblies, Related Materials and Processes

For rules and details of the IECQ visit www.iecq.org

Schedule of Scope to Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L ULTW 16.0003-08

CB Certificate No.: 50600329 ITL

Schedule Number: IECQ-L ULTW 16.0003-08-S Rev No.: 3 Revision Date: 2022/07/13 Page 1 of 1

Appendix-1 (50600329 ITL) Schedule of Scope to Certificate of Approval

Description test	Standard
Transmission Electron Microscope (TEM)	T-TEM-3
Scanning Electron Microscope (SEM)	T-SEM-3
Energy Dispersive Spectrometry of X-ray (EDS)	T-TEM-3 / T-SEM-3
Focused Ion Beam microscope (FIB)	T-FIB-3
X-Ray	T-EFA-3
EMMI-InGaAs	T-EFA-3
Optical Beam Induced Resistance Change (OBIRCH)	T-EFA-3
Scanning Acoustic Tomography (SAT)	T-EFA-3
Optical Microscope (OM)	T-OMI-3
3D Optical Microscope (3D OM)	T-LAB-3
Chemical Treatment	T-LAB-3

Technical Reviewer of DQS:	Michael Chou	Date:	07/13/2022

